

SEQUENTIAL ELEMENTS

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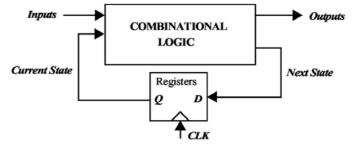
Sequential Elements - Outline

- Background
 - Timing, terminology, classification
- Static Flipflops
 - Latches
 - Registers
- Dynamic Flipflops
 - **III** Latches
 - Registers

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FSM with Positive Edge Triggered Registers





- Flip-flops provide memory/state
- VLSI uses predominantly D-type flip-flops

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Memory elements

- Store a temporary value, remember a state
- Typically controlled by clock.
- May have load signal, etc.
- In CMOS, memory is created by:
 - capacitance (dynamic);
 - feedback (static).
- Also see http://en.wikipedia.org/wiki/Flip-flop_(electronics)

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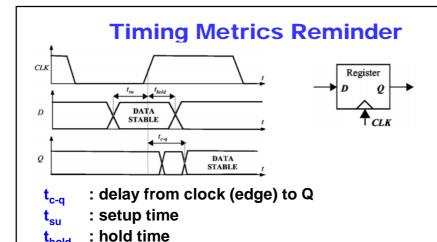
Variations in memory elements

- Form of required clock signal.
- How behavior of data input around clock affects the stored value.
- When the stored value is presented to the output.
- Whether there is ever a combinational path from input to output.

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 t_{plogic} : worst case propagation delay of logic

t_{cd}: best case propagation delay

(contamination delay)

T: clock period

 $\begin{aligned} & T \geq t_{c-q} + t_{plogic} + t_{su} \\ & t_{cdregister} + t_{cdlogic} \geq t_{hold} \end{aligned}$

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Latches vs. Registers

Latch

Level-sensitive

Transparent when clock is active

Clock active high: positive latch

Clock active low: negative latch

Faster, smaller

Register

Edge-triggered

Input and output isolated

Sampling on 0 → 1 clock: positive edge triggered

Sampling on 1 → 0 clock: negative edge triggered

Safer

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Static vs. Dynamic Memory Elements

Static

Operate through positive feedback

Preserve state as long as power is on

Can work when clock is off

More robust

Dynamic

Store charge on (parasitic) capacitor

Charge leaks away (in milliseconds)

Clock must be kept running (for periodic refresh)

Faster, smaller

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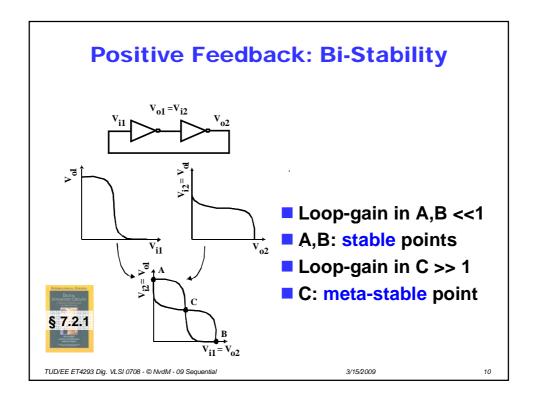
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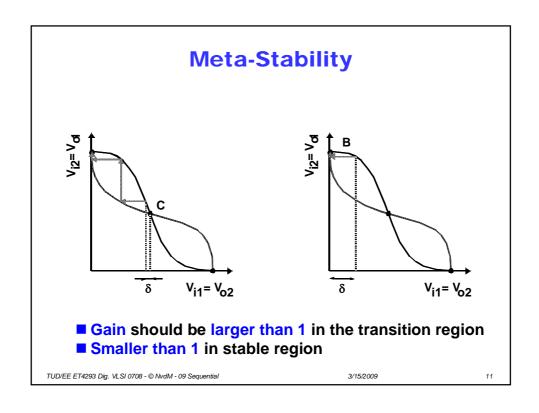
Static Flipflops

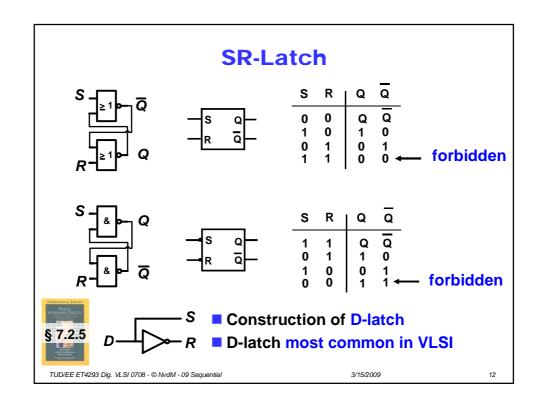
- **■**Latches
- **Registers**

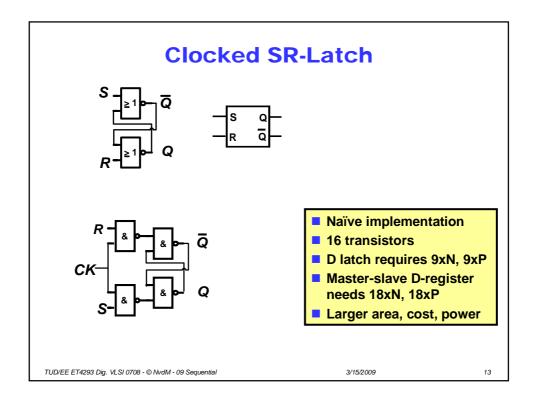
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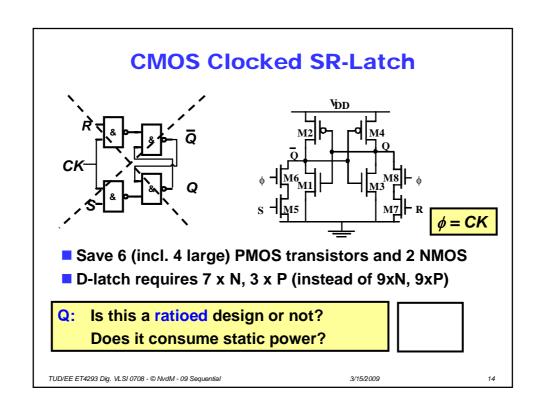
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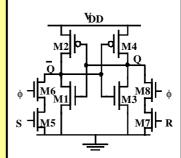






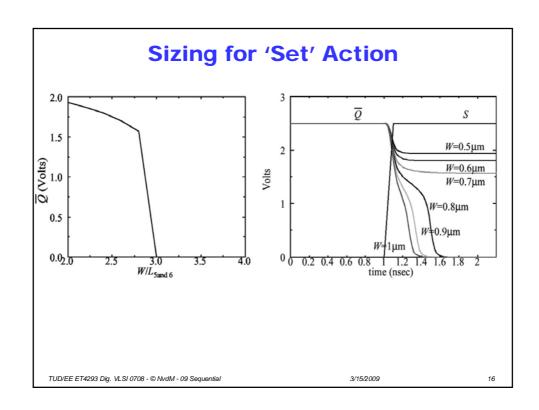
Sizing for 'Set' Action

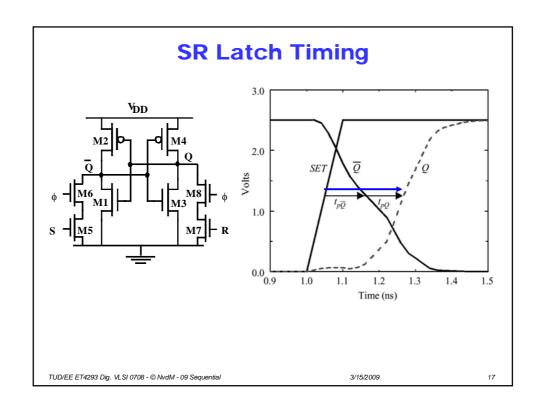
- M₃-M₄ form conventional inverter
- Model M₅-M₆ as one equivalent (double length) transistor M_{56} Assume Q = 0 \rightarrow M_1 is off, M_2 is on
- M₂-M₅₆ operate like ratioed pseudo **NMOS** inverter
- Latch switches when M₅₆ pulls input of M₃-M₄ below their switching threshold (assume V_{DD}/2)
- Positive feedback amplifies switching
- M₂ and M₅₆ both in velocity saturation around $V_Q = V_{DD}/2$

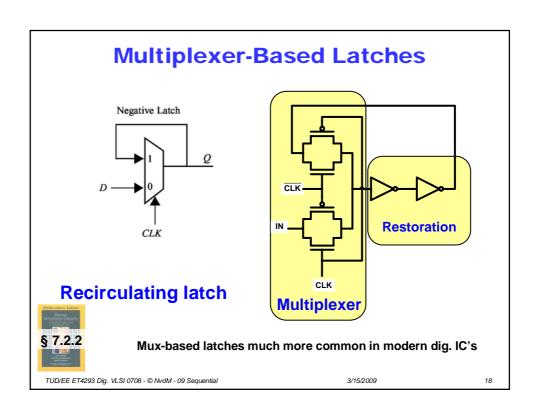


$$k'_{n} \left(\frac{W}{L}\right)_{5-6} \left((V_{DD} - V_{Tn}) V_{DSATn} - \frac{V_{DSATn}^{2}}{2} \right) = k'_{p} \left(\frac{W}{L}\right)_{2} \left((-V_{DD} - V_{Tp}) V_{DSATp} - \frac{V_{DSATp}^{2}}{2} \right)$$

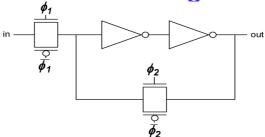
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Recirculating latch



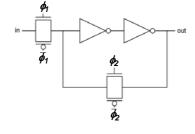
- Quasi-static, static on one phase
- Feedback restores value
- Requires 4 x N, 4 x P, minimum size (compare 7 x N, 3 x P, non-minimum size)
- lacktriangledown ϕ_1 and ϕ_2 inverse but should be non-overlapping
- Can suffer from charge sharing (when ϕ not non-overlapping)
 - Output connected directly to input
 - C_{in} and C_{load} form communicating vessels

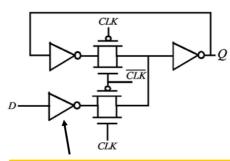
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Insensitive for Charge Sharing





■ Non ratioed

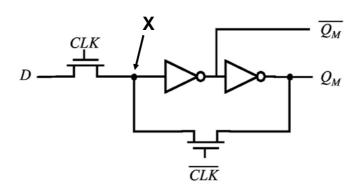
Uni-directionality of this inverter prevents coupling between Q and D

High load to CLK

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Recirculating NMOS Latch.



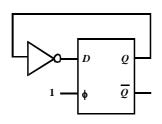
- Degraded 1 at X
- Lower noise margin, higher delay, power

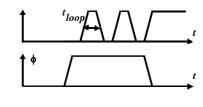
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Latch Designs can Suffer from Race Problems





Signal can race around during $\phi = 1$

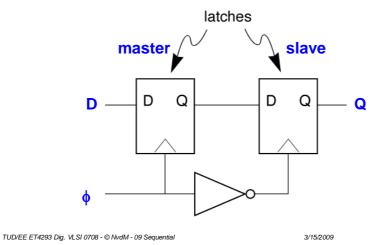
§ 7.2.3

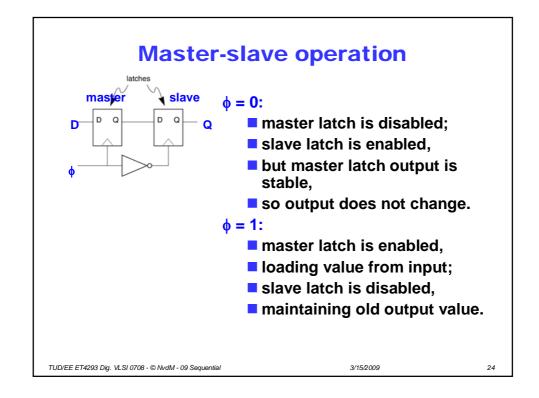
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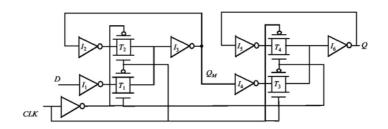


- Not transparent—use multiple storage elements to isolate output from input.
- Master-slave, edge triggered principle





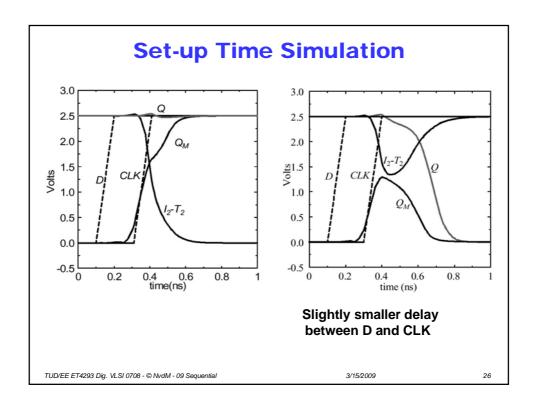
Transistor Level Master Slave Positive Edge Triggered Register

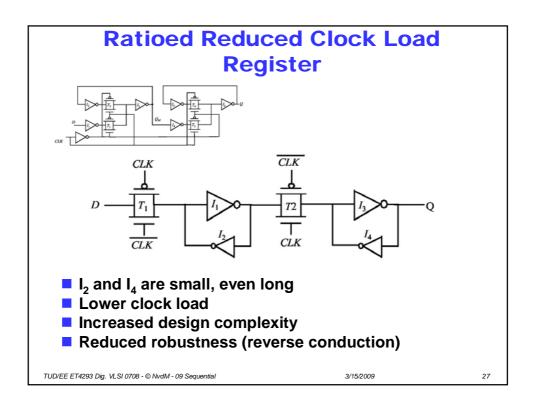


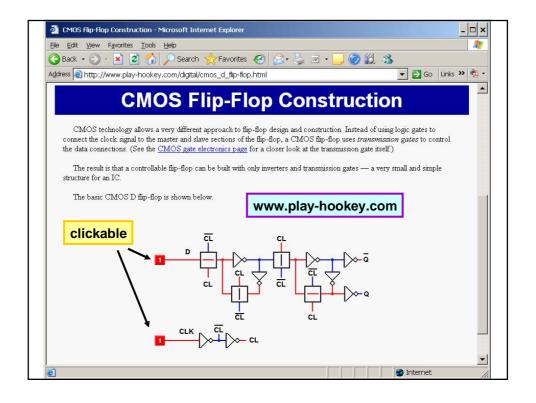
- Robust Design
- Can eliminate I₁ and I₄, however, they make design more robust (avoid charge sharing, robust input)
- High Clock Load (8 x)

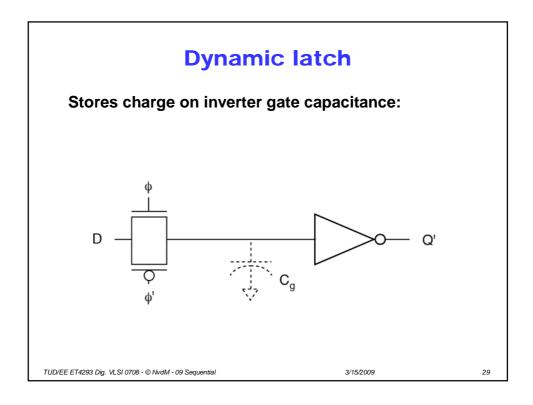
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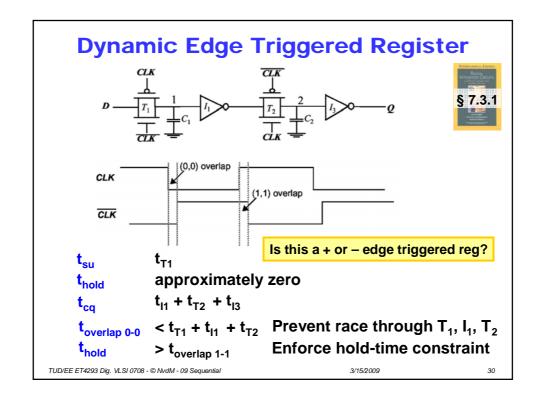
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Summary

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